Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/538,884	AUCHTER ET AL.	
Examiner	Art Unit	

3679

David E. Bochna

	SEARCHED			
Class	Subclass	Date	Examiner	
285	420	9/29/2006	DB	
	223			
	424			
123	470			
			•	

INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner
		<del> </del>	
	:		

(INCLUDING SEARC	DATE	EXMR
	•	
•		
		ļ
·		
	•	
		<del> </del>
		ļ